

**Notice of References Cited**

Application/Control No.

10/533,918

Applicant(s)/Patent Under  
Reexamination  
OZAWA ET AL.

Examiner

Nguyen T. Ha

Art Unit

2831

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0152882	07-2006	Takeda et al.	361/272
*	B	US-6,274,061	08-2001	Tamamitsu, Kenji	252/62.2
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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